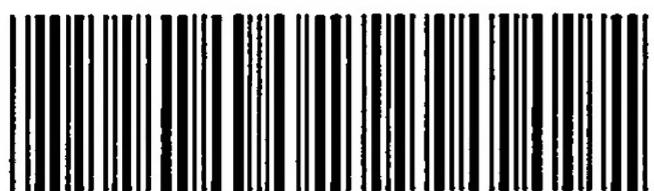


## **Search Notes**



**Application/Control No.**

10/628,899

Examiner

DAVID VU

**Applicant(s)/Patent under  
Reexamination**

CHEN ET AL.

## Art Unit

2818

**SEARCHED**

## **SEARCH NOTES (INCLUDING SEARCH STRATEGY)**

## **INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner